## Notice of References Cited Application/Control No. 10/535,423 Applicant(s)/Patent Under Reexamination OKAHARA ET AL. Examiner EDMUND H. LEE 1791 Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,143,226	11-2000	Fujimoto et al.	264/255
*	В	US-2006/0076712	04-2006	Yonemochi et al.	264/255
*	С	US-6,180,043	01-2001	Yonemochi et al.	264/255
*	D	US-5,174,933	12-1992	Toh et al.	264/40.5
*	Е	US-5,071,603	12-1991	Kurumaji et al.	264/40.5
*	F	US-6,676,877	01-2004	Thompson, John A.	264/255
	G	US-			
	Н	US-			
	-	US-			
	٦	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Ø					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

	NON-I ATENT BOOOMENTO							
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)						
	U							
	V							
	w							
	х							

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.